

REVISIONS			
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
C	Redrawn with changes. Add device types 04 and 05. Add case outline H. Editorial changes throughout.	94-03-04	M.A. Frye
D	Add device types 06 and 07. Table I changes. Editorial changes throughout.	95-01-18	M.A. Frye
E	Changes in accordance with NOR 5962-R037-96.	96-01-11	M.A. Frye
F	Changes in accordance with NOR 5962-R072-96.	96-03-15	M.A. Frye
G	Update boiler plate and incorporate previous 2 NORs. Redrawn. Updated bulletin. -lgt	98-06-26	Ray Monnin

THE ORIGINAL FIRST SHEET OF THIS DRAWING HAS BEEN REPLACED.

REV																				
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REV STATUS OF SHEETS	REV	G	G	G	G	G	G	G	G	G	G	G	G							
	SHEET	1	2	3	4	5	6	7	8	9	10	11								
PMIC N/A	PREPARED BY Rick Officer	DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216 MICROCIRCUIT, LINEAR, SINGLE POWER MOSFET DRIVER, MONOLITHIC SILICON																		
STANDARD MICROCIRCUIT DRAWING THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE AMSC N/A	CHECKED BY Charles E. Besore																			
	APPROVED BY Michael A. Frye																			
	DRAWING APPROVAL DATE 89-08-16																			
	REVISION LEVEL G	SIZE A	CAGE CODE 67268	5962-88770																
		SHEET 1 OF 11																		

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DISTRIBUTION STATEMENT A Approved for public release; distribution is unlimited.

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1.3 Absolute maximum ratings - continued.

Power dissipation (P_D) :

Case outline H.....	650 mW <u>1/</u>
Case outline P.....	800 mW <u>2/</u>
Case outline 2.....	1.8 W <u>3/</u>
Lead temperature (soldering, 10 seconds).....	+300°C
Junction temperature range (T _J).....	-55°C to +150°C

1.4 Recommended operating conditions.

Supply voltage range.....	4.5 V dc ≤ V _S ≤ 18 V dc
Ambient operating temperature range (T _A).....	-55°C to +125°C

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, and handbooks. The following specification, standards, and handbooks form a part of this drawing to the extent specified herein. Unless otherwise specified, the issues of these documents are those listed in the issue of the Department of Defense Index of Specifications and Standards (DoDISS) and supplement thereto, cited in the solicitation.

SPECIFICATION

DEPARTMENT OF DEFENSE

MIL-PRF-38535 - Integrated Circuits, Manufacturing, General Specification for.

STANDARDS

DEPARTMENT OF DEFENSE

- MIL-STD-883 - Test Method Standard Microcircuits.
- MIL-STD-973 - Configuration Management.
- MIL-STD-1835 - Interface Standard For Microcircuit Case Outlines.

HANDBOOKS

DEPARTMENT OF DEFENSE

- MIL-HDBK-103 - List of Standard Microcircuit Drawings (SMD's).
- MIL-HDBK-780 - Standard Microcircuit Drawings.

(Unless otherwise indicated, copies of the specification, standards, and handbooks are available from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

- 1/ Derate linearly at 6.5 mW/°C above T_A = +50°C.
- 2/ Derate linearly at 8 mW/°C above T_A = +50°C.
- 3/ Derate linearly at 18 mW/°C above T_A = +50°C.

STANDARD MICROCIRCUIT DRAWING DEFENSE SUPPLY CENTER COLUMBUS COLUMBUS, OHIO 43216-5000	SIZE A		5962-88770
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3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with MIL-PRF-38535, appendix A for non-JAN class level B devices and as specified herein. Product built to this drawing that is produced by a Qualified Manufacturer Listing (QML) certified and qualified manufacturer or a manufacturer who has been granted transitional certification to MIL-PRF-38535 may be processed as QML product in accordance with the manufacturers approved program plan and qualifying activity approval in accordance with MIL-PRF-38535. This QML flow as documented in the Quality Management (QM) plan may make modifications to the requirements herein. These modifications shall not affect form, fit, or function of the device. These modifications shall not affect the PIN as described herein. A "Q" or "QML" certification mark in accordance with MIL-PRF-38535 is required to identify when the QML flow option is used.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535, appendix A and herein.

3.2.1 Case outline(s). The case outline(s) shall be in accordance with 1.2.2 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full ambient operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-PRF-38535, appendix A. The part shall be marked with the PIN listed in 1.2 herein. In addition, the manufacturer's PIN may also be marked as listed in MIL-HDBK-103 (see 6.6 herein). For packages where marking of the entire SMD PIN number is not feasible due to space limitations, the manufacturer has the option of not marking the "5962-" on the device.

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-HDBK-103 (see 6.6 herein). The certificate of compliance submitted to DSCC-VA prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-PRF-38535, appendix A and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-PRF-38535, appendix A shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DSCC-VA shall be required in accordance with MIL-PRF-38535, appendix A.

3.9 Verification and review. DSCC, DSCC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535, appendix A.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C ≤ T _A ≤ +125°C 4.5 ≤ V _S ≤ 18 V unless otherwise specified		Group A subgroups	Device type	Limits		Unit
						Min	Max	
Logic "1" input voltage	V _{IH}			1, 2, 3	01-05	2.4		V
					06, 07	3.5		
Logic "0" input voltage	V _{IL}			1, 2, 3	01-05		0.8	V
					06, 07		2.0	
Input voltage range	V _{IN} (max)			1, 2, 3	01	0	V _S	V
					02, 03 04, 05	-5	V _S +0.3	
Input current	I _{IN}	0 V ≤ V _{IN} ≤ V _S		1	ALL		±1	μA
							±10	
		-5 V ≤ V _{IN} ≤ 0 V		1, 2, 3	02, 03, 07		±10	mA
High output voltage	V _{OH}	R _L = ∞	1/	1, 2, 3	ALL	V _S - 25 mV		V
Low output voltage	V _{OL}	R _L = ∞	1/	1, 2, 3	ALL		25	mV
Output resistance	R _{O1}	V _{IN} = 0.8 V I _{OUT} = 10 mA	V _S = 18 V	1	01, 03		2.5	Ω
				2, 3			5.0	
				1	02		2.8	
				2, 3			5.0	
				1	04, 05		1.5	
				2, 3			2.2	
				1	06, 07		2.5	
				2, 3			3.6	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C ≤ T _A ≤ +125°C 4.5 ≤ V _S ≤ 18 V unless otherwise specified		Group A subgroups	Device type	Limits		Unit	
						Min	Max		
Output resistance	R _{O2}	V _{IN} = 2.4 V I _{OUT} = 10 mA	V _S = 18 V	1	01, 02		2.5	Ω	
				2, 3			5.0		
				1	03		2.8		
				2, 3			5.0		
		1	04, 05		1.5				
		2, 3			2.2				
		1	06, 07		1.7				
		2, 3			2.7				
Quiescent supply current	I _{S1}	V _{IN} = 3.0 V		1	01		5.0	mA	
				2, 3			12		
				1	02, 03 04, 05 06, 07		1.5		
				2, 3			3.0		
				1		01			0.5
				2, 3					1.3
	I _{S2}	V _{IN} = 0.0 V		1	02, 03		0.15		
				2, 3			0.40		
				1	04, 05 06, 07		0.15		
				2, 3			0.4		
				9		01			35
				10, 11					70
Rise time	t _R	2/ See figures 2 and 3 V _S = 18 V	C _L = 2500 pF	9	02, 03		35	ns	
				10, 11			60		
				9	04, 05		75		
				10, 11			100		
		C _L = 15,000 pF	9	06, 07		75			
			10, 11			120			
			C _L = 10,000 pF	9					
				10, 11					

See footnotes at end of table.

**STANDARD
MICROCIRCUIT DRAWING**
DEFENSE SUPPLY CENTER COLUMBUS
COLUMBUS, OHIO 43216-5000

SIZE
A

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C ≤ T _A ≤ +125°C 4.5 ≤ V _S ≤ 18 V unless otherwise specified		Group A subgroups	Device type	Limits		Unit			
						Min	Max				
Fall time	t _F	2/ See figures 2 and 3 V _S = 18 V	C _L = 2500 pF	9	01		35	ns			
				10, 11			70				
				9	02, 03		35				
				10, 11			60				
			C _L = 15,000 pF	9	04, 05		75				
				10, 11			100				
				C _L = 10,000 pF	9	06, 07			75		
			10, 11				120				
			Delay time	t _{D1}	2/ See figures 2 and 3 V _S = 18 V	9	01, 02 03			75	ns
									10, 11		
9	04, 05 06, 07					60					
		10, 11					80				
9	01					75					
		10, 11					120				
t _{D2}	9	02, 03				75					
				10, 11			100				
	9	04, 05 06, 07				60					
				10, 11			80				

1/ Guaranteed by design

2/ Subgroups 10 and 11 are guaranteed if not tested to the limits as specified in table I herein.

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Device types	01-07	01-07	01-03
Case outlines	H	P	2
Terminal number	Terminal symbol		
1	V _s	VS	NC
2	INPUT	INPUT	NC
3	NC	NC	VS
4	GND	GND	NC
5	NC	GND	NC
6	NC	OUTPUT	INPUT
7	GND	OUTPUT	NC
8	OUTPUT	VS	NC
9	OUTPUT	-----	GND
10	V _s	-----	NC
11	-----	-----	NC
12	-----	-----	NC
13	-----	-----	GND
14	-----	-----	NC
15	-----	-----	OUTPUT
16	-----	-----	OUTPUT
17	-----	-----	NC
18	-----	-----	NC
19	-----	-----	VS
20	-----	-----	NC

NC = No connection

FIGURE 1. Terminal connections.

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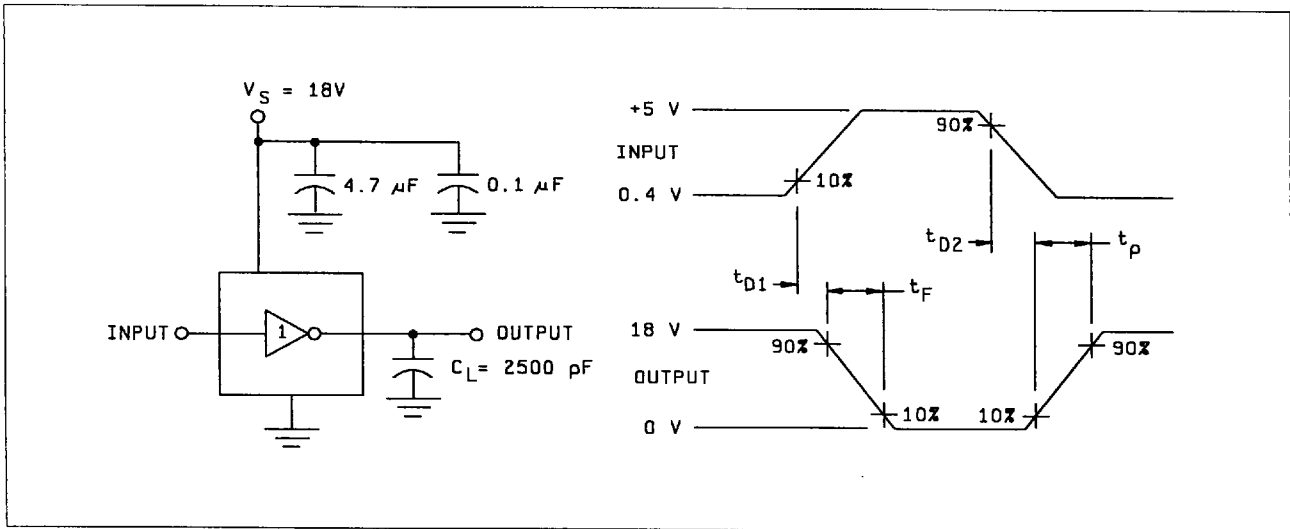


FIGURE 2. Inverting driver switching time.

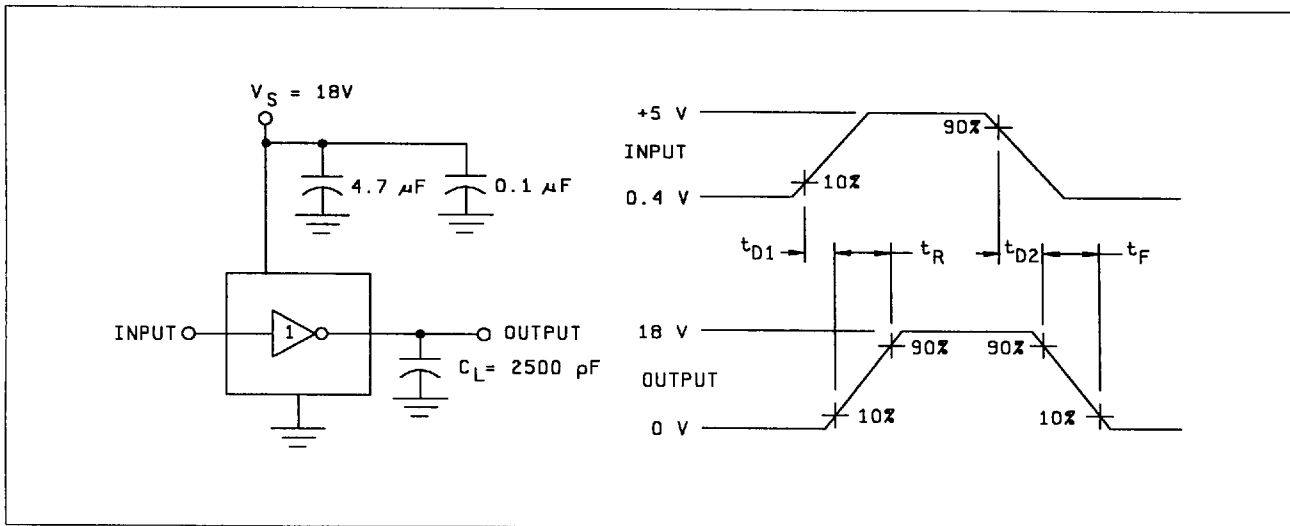


FIGURE 3. Noninverting driver switching time.

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4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015 of MIL-STD-883.

(2) $T_A = +125^\circ\text{C}$, minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 4, 5, 6, 7, and 8 in table I, method 5005 of MIL-STD-883 shall be omitted.

4.3.2 Groups C and D inspections.

a. End-point electrical parameters shall be as specified in table II herein.

b. Steady-state life test conditions, method 1005 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005 of MIL-STD-883.

(2) $T_A = +125^\circ\text{C}$, minimum.

(3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-PRF-38535, appendix A.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-973 using DD Form 1692, Engineering Change Proposal.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (in accordance with MIL-STD-883, method 5005, table I)
Interim electrical parameters (method 5004)	-----
Final electrical test parameters (method 5004)	1*, 2, 3
Group A test requirements (method 5005)	1, 2, 3, 9, 10**, 11**
Groups C and D end-point electrical parameters (method 5005)	1

* PDA applies to subgroup 1.

** Subgroups 10 and 11, if not tested, shall be guaranteed to the specified limits in table I.

6.4 Record of users. Military and industrial users shall inform Defense Supply Center Columbus when a system application requires configuration control and the applicable SMD. DSCC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DSCC-VA, telephone (614) 692-0525.

6.5 Comments. Comments on this drawing should be directed to DSCC-VA, Columbus, Ohio 43216-5000, or telephone (614) 692-0674.

6.6 Approved sources of supply. Approved sources of supply are listed in MIL-HDBK-103. The vendors listed in MIL-HDBK-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DSCC-VA.

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STANDARD MICROCIRCUIT DRAWING BULLETIN

DATE : 98-06-26

Approved sources of supply for SMD 5962-88770 are listed below for immediate acquisition information only and shall be added to MIL-HDBK-103 during the next revision. MIL-HDBK-103 will be revised to include the addition or deletion of sources. The vendors listed below have agreed to this drawing and a certificate of compliance has been submitted to and accepted by DSCC-VA. This bulletin is superseded by the next dated revision of MIL-HDBK-103.

Standard microcircuit drawing PIN <u>1</u> /	Vendor CAGE number	Vendor similar PIN <u>2</u> /
5962-8877001HA	<u>3</u> /	MIC429AWBQ
5962-8877001PA	<u>3</u> /	MIC429AJBQ
5962-88770012A	<u>3</u> /	TSC429MNP/883
5962-8877002HA	<u>3</u> /	MIC4429AWBQ
5962-8877002PA	1ES66	MAX4429MJA/883B
5962-88770022C	1ES66	MAX4429MLP/883B
5962-8877003HA	<u>3</u> /	MIC4420AWBQ
5962-8877003PA	60496	MIC4420AJBQ
	1ES66	MAX4420MJA/883B
5962-88770032C	1ES66	MAX4420MLP/883B
5962-8877004HA	<u>3</u> /	MIC4451AWBQ
5962-8877004PA	<u>3</u> /	MIC4451AJBQ
5962-8877005HA	<u>3</u> /	MIC4452AWBQ
5962-8877005PA	<u>3</u> /	MIC4452AJBQ

See footnotes at end of table.

STANDARD MICROCIRCUIT DRAWING SOURCE APPROVAL BULLETIN - Continued

Standard microcircuit drawing PIN <u>1/</u>	Vendor CAGE number	Vendor similar PIN <u>2/</u>
5962-8877006HA	<u>3/</u>	MIC44R21AWBQ
5962-8877006PA	<u>3/</u>	MIC44R21AJBQ
5962-8877007HA	<u>3/</u>	MIC44R22AWBQ
5962-8877007PA	<u>3/</u>	MIC44R22AJBQ

- 1/ The lead finish shown for each PIN representing a hermetic package is the most readily available from the manufacturer listed for that part. If the desired lead finish is not listed contact the vendor to determine its availability.
- 2/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.
- 3/ Not available from an approved source of supply.

Vendor CAGE number

Vendor name and address

60496

Micrel Inc.
560 Oakmead Pkwy
Sunnyvale, CA 94086

1ES66

Maxim Integrated Products Inc.
120 San Gabriel DR
Sunnyvale, CA 94086-5125

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